Sharper Image Corporation

NYCFI-DUO

Model Number: SI367

Prepared for : Sharper Image Corporation
650 Davis Street San Francisco, CA 94111

Prepared By : Audix Technology (Shenzhen) Co., Ltd.
No. 6, Ke Feng Rd., 52 Block,
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Report Number : ACS-F04307
Date of Test : Sep.09~12, 2004
Date of Report : Oct.12, 2004

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TEST REPORT DECLARATION

Applicant	:	Sharper Image Corporation
Manufacturer	:	IDT Electronic Products Ltd.
EUT Description	:	NYCFI-DUO
		(A) MODEL NO. : SI367
		(B) SERIAL NO. : F2004101201
		(C) POWER SUPPLY : DC 3V

Test Procedure Used:

FCC Rules and Regulations Part 15 Subpart C Apr, 2004.

The device described above is tested by Audix Technology (Shenzhen) Co., Ltd. to determine the maximum emission levels emanating from the device. The maximum emission levels are compared to the FCC Part 15 Subpart C limits for radiated and conducted emissions.
The test results are contained in this test report and Audix Technology (Shenzhen) Co., Ltd. is assumed full responsibility for the accuracy and completeness of tests. Also, this report shows that EUT is technically compliant with FCC requirements.

This report applies to above tested sample only. This report shall not be reproduced in part without written approval of Audix Technology (Shenzhen) Co., Ltd.
This report must not be used by the applicant to claim product endorsement by NVLAP or any agency of the U.S. Government.

Date of Test : Sep.09~12, 2004

Prepared by : Elsa Wu / Assistant

Reviewer : Lake Wang / Supervisor

AUDIX® 信華科技(深圳)有限公司
Audix Technology (Shenzhen) Co., Ltd.
EMC 部門報告專用章
Stamp only for EMC Dept. Report
Signature:

Approved & Authorized Signer : Alex Deng / Assistant Manager

Name of the Representative of the Responsible Party : _____

Signature : _____

1. GENERAL INFORMATION

1.1. Description of Device (EUT)

Description	:	NYCFI-DUO
Model Number	:	SI367
Applicant	:	Sharper Image Corporation 650 Davis Street San Francisco, CA 94111
Manufacturer	:	IDT Electronic Products Ltd. Block C, 9/F Kaiser Estate, Phase 1, 41 Man Yue Street, Hunghom, Kowloon, Hong Kong
Date of Test	:	Sep.09~12, 2004

1.2. Test Facility

Site Description

3m Anechoic Chamber	:	Certificated by FCC, USA Registration Number : 90454 Aug. 15, 2003
3m & 10m Anechoic Chamber	:	Certificated by FCC, USA Registration Number : 794232 Mar. 15, 2004
EMC Lab.	:	Certificated by DATech, German Registration Number : DAT-P-091/99-01 Feb. 02, 2004 Certificated by NVLAP, USA NVLAP Code: 200372-0 Mar. 31, 2004 Certificated by Nemko, Norway Aut. No.: ELA135 April. 22, 2004 Certificated by Industry Canada Registration Number: IC 5183 Jul. 28, 2004
Name of Firm	:	Audix Technology (Shenzhen) Co., Ltd.
Site Location	:	No. 6, Ke Feng Rd., 52 Block, Shenzhen Science & Industrial Park, Nantou, Shenzhen, Guangdong, China

1.3. Measurement Uncertainty

Conducted Emission Uncertainty	=	± 2.66dB
Radiated Emission Uncertainty	=	± 4.26dB

2. POWER LINE CONDUCTED EMISSION TEST

According to Paragraph (f) of FCC Part 15 section 15.107, Tests to demonstrate compliance with the conducted limits are not required for devices which only employ battery power for operation and which do not operate from the AC power lines or contain provisions for operation while connected to the AC power lines.

3. RADIATED EMISSION TEST

3.1. Test Equipment

The following test equipments are used during the radiated emission Test：

3.1.1. For Anechoic Chamber

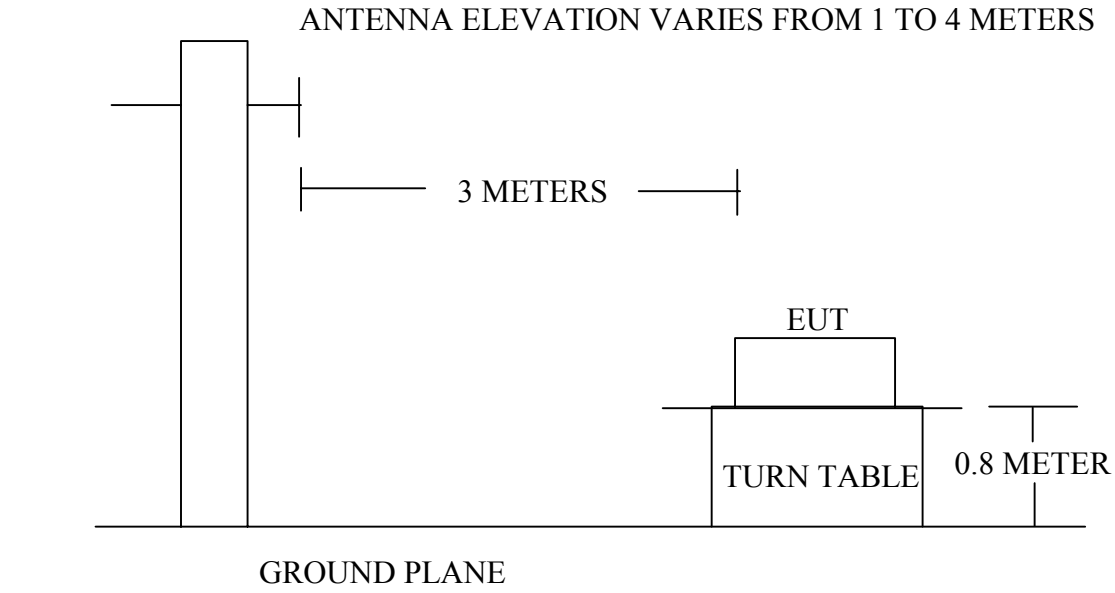
Item	Equipment	Manufacturer	Model No.	Serial No.	Last Cal.	Cal. Interval
1.	EMI Spectrum	HP	8591EM	3628A00914	May 24, 04	1 Year
2.	Test Receiver	Rohde & Schwarz	ESVS10	834468/011	May 24, 04	1 Year
3.	Amplifier	HP	8447D	2944A07794	Sep.16, 04	1/2 Year
4.	Bilog Antenna	Schaffner	CBL6111C	2598	Jan. 13, 04	1 Year
5.	PC	N/A	586ATX3	N/A	N/A	N/A
6.	Printer	HP	Laserjet6P	SGCF019673	N/A	N/A
7.	RF Cable	MIYAZAKI	5D-2W	3# Chamber No.1	July 31, 04	1/2 Year
8.	RF Cable	MIYAZAKI	5D-2W	3# Chamber No.2	July 31, 04	1/2 Year
9.	RF Cable	FUJIKURA	RG-55/U	3# Chamber No.3	July 31, 04	1/2 Year
10.	RF Cable	FUJIKURA	RG-55/U	3# Chamber No.4	July 31, 04	1/2 Year
11.	Coaxial Switch	Anritsu	MP59B	M73989	May 27, 04	1/2 Year
12.	Spectrum	Agilent	E4407B	MY41440292	May 24, 04	1 Year
13.	Amp	HP	8449B	3008A00863	May 24. 04	1 Year
14.	Antenna	EMCO	3115	9607-4877	Jun. 15, 04	1.5 Year

3.2. Block Diagram of Test Setup

3.2.1. Block Diagram of connection between EUT and simulators

(EUT: NYCFI-DUO)

3.2.2. Anechoic Chamber Setup Diagram



3.3. Radiated Emission Limit (Class C)

FREQUENCY MHz	DISTANCE Meters	FIELD STRENGTHS LIMIT	
		μV/m	dB(μV)/m
30 ~ 88	3	100	40.0
88 ~ 216	3	150	43.5
216 ~ 960	3	200	46.0
960 ~ 1000	3	500	54.0
Above 1000	3	Local Oscillator: 114.0 dB(μV)/m (Peak) 94.0 dB(μV)/m (Average) Other: 74.0 dB(μV)/m (Peak) 54.0 dB(μV)/m (Average)	

Remark： (1) Emission level dBμV = 20 log Emission level μV/m
(2) The smaller limit shall apply at the cross point between two frequency bands.
(3) Distance is the distance in meters between the measuring instrument, antenna and the closest point of any part of the device or system.

3.4. EUT Configuration on Test

The following equipment are installed on Radiated Emission Test to meet the commission requirements and operating regulations in a manner which tends to maximize its emission characteristics in normal application.

3.4.1. NYCFI-DUO (EUT)

Model Number	:	SI367
Serial Number	:	F2004101201
Manufacturer	:	IDT Electronic Products Ltd.

3.5. Operating Condition of EUT

3.5.1. Setup the EUT as shown in Section 3.2..

3.5.2. Let the EUT work in test modes (On (Tx)/On (Rx)) and test it.

3.6. Test Procedure

The EUT and its simulators are placed on a turn table, which is 0.8 meter high above ground. The turn table can rotate 360 degrees to determine the position of the maximum emission level. The EUT is set 3 meters away from the receiving antenna, which is mounted on a antenna tower. The antenna can be moved up and down between 1 meter and 4 meters to find out the maximum emission level. Broadband antenna (calibrated bilog antenna) is used as receiving antenna. Both horizontal and vertical polarization of the antenna is set on Test. In order to find the maximum emission levels, all of the interface cables must be manipulated according to ANSI C63.4-2001 on radiated emission Test.

The bandwidth of the EMI test receiver (R&S ESVS20) is set at 120KHz.

The frequency range from 30MHz to 1000MHz and above 1000MHz are checked.

The test modes (On (Tx)/On (Rx)) is tested in Anechoic Chamber and all the scanning waveforms are attached in Appendix I.

3.7. Radiated Emission Test Results

PASS.

The frequency range from 30MHz to 1000MHz is investigated.
Please see the following pages.

Date of Test :	Sep.12, 2004	Temperature :	24℃
EUT :	NYCFI-DUO	Humidity :	56%
Model No. :	SI367	Test Mode :	On (Tx)
Test Engineer:	Seco		

Frequency MHz	Probe Factor dB/m	Cable Loss dB	Meter Reading Horizontal dBμV	Emission Level Horizontal dBμV/m	Over Limits dBμV/m	Limits dBμV/m
433.600	**16.71**	**4.89**	**51.07**	**72.67**	**-8.15**	**80.82**
867.200	22.07	7.26	14.67	44.00	-16.82	60.82

Remark: 1. Emission Level = Probe Factor + Meter Reading+Cable Loss
2.The bandwidth of the RBW is set at 120KHz and VBW is set at 300KHz.

Frequency MHz	Probe Factor dB/m	Cable Loss dB	Meter Reading Vertical dBμV	Emission Level Vertical dBμV/m	Over Limits dBμV/m	Limits dBμV/m
433.600	**16.26**	**4.89**	**49.95**	**71.10**	**-9.72**	**80.82**
837.200	21.92	7.30	11.38	40.60	-20.22	60.82

Remark: 1. Emission Level = Probe Factor + Meter Reading+Cable Loss
2.The bandwidth of the RBW is set at 120KHz and VBW is set at 300KHz.

Reviewer: Cake Wang

Date of Test :	Sep.12, 2004	Temperature :	24℃
EUT :	NYCFI-DUO	Humidity :	56%
Model No. :	SI367	Test Mode :	On (Rx)
Test Engineer:	Seco		

Frequency MHz	Probe Factor dB/m	Cable Loss dB	Meter Reading Horizontal dBμV	Emission Level Horizontal dBμV/m	Over Limits dBμV/m	Limits dBμV/m
31.940	**19.93**	**1.07**	**4.71**	**25.71**	**-14.29**	**40.00**
67.830	6.12	1.61	9.05	16.78	-23.22	40.00
128.940	12.28	2.30	4.78	19.36	-24.14	43.50
261.830	13.56	3.53	3.91	21.00	-25.00	46.00
436.430	16.56	4.96	3.83	25.35	-20.65	46.00
630.430	19.54	6.48	3.93	29.95	-16.05	46.00

Remark: 1. Emission Level = Probe Factor + Meter Reading+Cable Loss
2.The bandwidth of the RBW is set at 120KHz and VBW is set at 300KHz.

Frequency MHz	Probe Factor dB/m	Cable Loss dB	Meter Reading Vertical dBμV	Emission Level Vertical dBμV/m	Over Limits dBμV/m	Limits dBμV/m
30.000	13.39	1.05	8.48	22.92	-17.08	40.00
53.280	6.32	1.41	9.61	17.34	-22.66	40.00
133.790	11.62	2.32	5.19	19.13	-24.37	43.50
424.790	16.27	4.78	4.79	25.84	-20.16	46.00
599.390	18.91	6.11	3.20	28.22	-17.78	46.00
715.790	**21.16**	**6.62**	**2.64**	**30.42**	**-15.58**	**46.00**

Remark: 1. Emission Level = Probe Factor + Meter Reading+Cable Loss
2.The bandwidth of the RBW is set at 120KHz and VBW is set at 300KHz.

Reviewer: Cake Wang

Date of Test :	Sep.09, 2004	Temperature :	24℃
EUT :	NYCFI-DUO	Humidity :	56%
Model No. :	SI367	Test Mode :	On (Tx)
Test Engineer:	Seco		

Frequency MHz	Probe Factor dB/m	Cable Loss dB	Meter Reading Horizontal dBμV	Emission Level Horizontal dBμV/m	Over Limits dBμV/m	Limits dBμV/m	Remark
1300.800	25.00	3.06	1.84	29.90	-32.00	61.90	Peak

Remark: 1. All readings are Peak values.
2. Emission Level = Probe Factor + Meter Reading+Cable Loss

Frequency MHz	Probe Factor dB/m	Cable Loss dB	Meter Reading Vertical dBμV	Emission Level Vertical dBμV/m	Over Limits dBμV/m	Limits dBμV/m	Remark
1300.800	25.00	3.06	2.14	30.20	-31.70	61.90	Peak
1734.400	26.69	1.99	2.52	31.20	-30.70	61.90	Peak

Remark: 1. All readings are Peak values.
2. Emission Level = Probe Factor + Meter Reading+Cable Loss

Reviewer: Lake Wang

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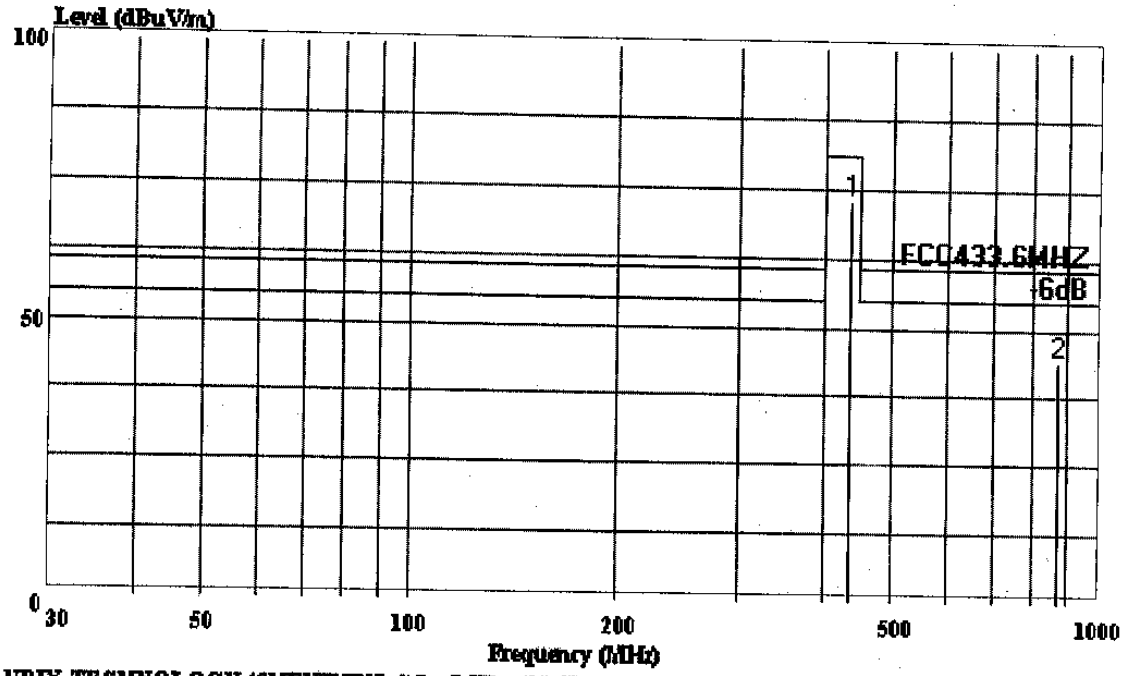
Data#: 2 File#: Sharper.EMI Date: 2004-09-12 Time: 11:40:20



AUDIX TECHNOLOGY (SHENZHEN) CO., LTD. (3# Chamber)

Trace: Ref Trace:

Condition: FCC433.6MHZ 3m 2598FACTOR HORIZONTAL
EUT : NYCFI-DUO
M/N : SI367
Power : Battery DC 3V
Engineer : Seco
Test Mode: On (Tx)
Memo : Temp:24'C Humi:56%
: Antpos:1.0m Tablepos:0'

Page: 1

	Freq	Level	Over Limit	Limit Line	Read Level	Probe Factor	Cable Loss
	MHz	dBuV/m	dB	dBuV/m	dBuV	dB	dB
1	433.600	72.67	-8.15	80.82	51.07	16.71	4.89
2	867.200	44.00	-16.82	60.82	14.67	22.07	7.26

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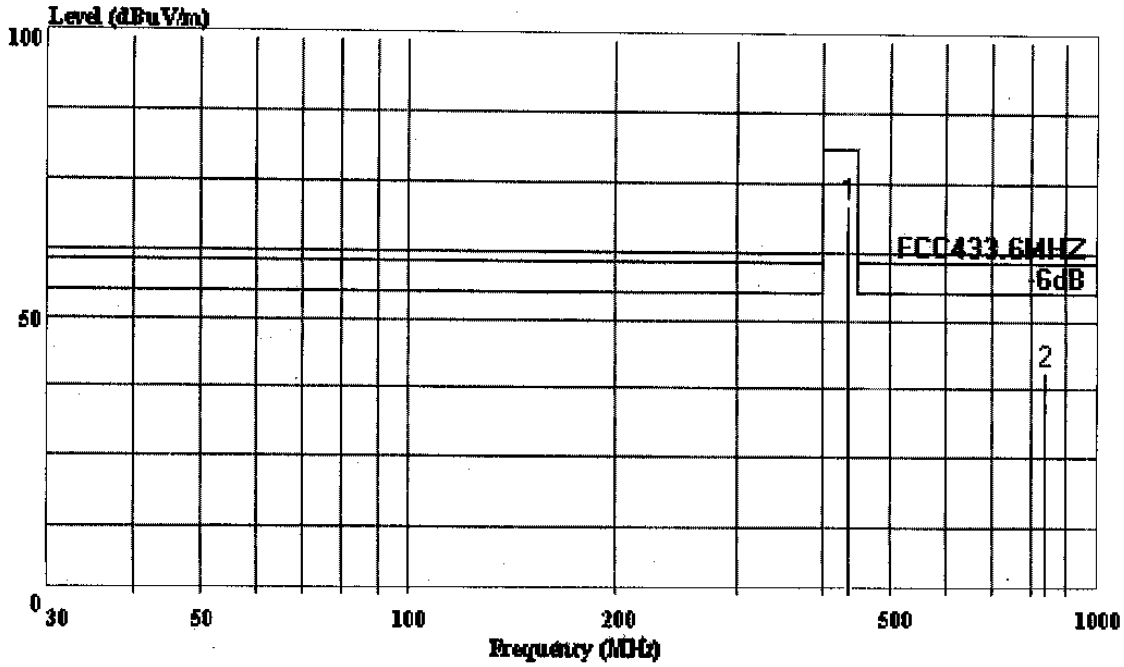
Data#: 4 File#: Sharper.EMI Date: 2004-09-12 Time: 11:56:22



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Trace: Ref Trace:

Condition: FCC433.6MHZ 3m 2598FACTOR VERTICAL
EUT : NYCFI-DUO
M/N : SI367
Power : Battery DC 3V
Engineer : Seco
Test Mode: On (Tx)
Memo : Temp:24'C Humi:56%
: Antpos:1.0m Tablepos:0'

Page: 1

	Freq	Level	Over Limit	Limit Line	Read Level	Probe Factor	Cable Loss
	MHz	dBuV/m	dB	dBuV/m	dBuV	dB	dB
1	433.600	71.10	-9.72	80.82	49.95	16.26	4.89
2	837.200	40.60	-20.22	60.82	11.38	21.92	7.30

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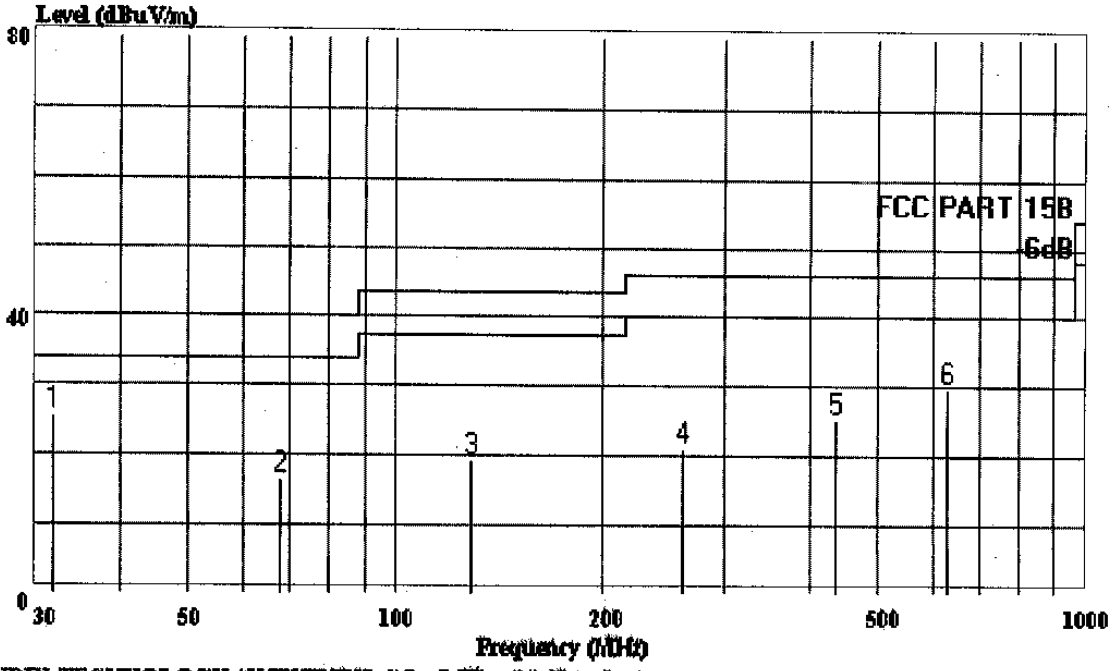
Data#: 8 File#: Sharper.EMI Date: 2004-09-12 Time: 12:15:41



AUDIX TECHNOLOGY (SHENZHEN) CO., LTD. (3# Chamber)

Trace: Ref Trace:

Condition: FCC PART 15B 3m 2598FACTOR HORIZONTAL
EUT : NYCFT-DUO
M/N : SI367
Power : Battery DC 3V
Engineer : Seco
Test Mode: On (Rx)
Memo : Temp:24'C Humi:56%
: Antpos:1.0m Tablepos:46'

Page: 1

	Freq	Level	Over Limit	Limit Line	Read Level	Probe Factor	Cable Loss
	MHz	dBuV/m	dB	dBuV/m	dBuV	dB	dB
1	31.940	25.71	-14.29	40.00	4.71	19.93	1.07
2	67.830	16.78	-23.22	40.00	9.05	6.12	1.61
3	128.940	19.36	-24.14	43.50	4.78	12.28	2.30
4	261.830	21.00	-25.00	46.00	3.91	13.56	3.53
5	436.430	25.35	-20.65	46.00	3.83	16.56	4.96
6	630.430	29.95	-16.05	46.00	3.93	19.54	6.48

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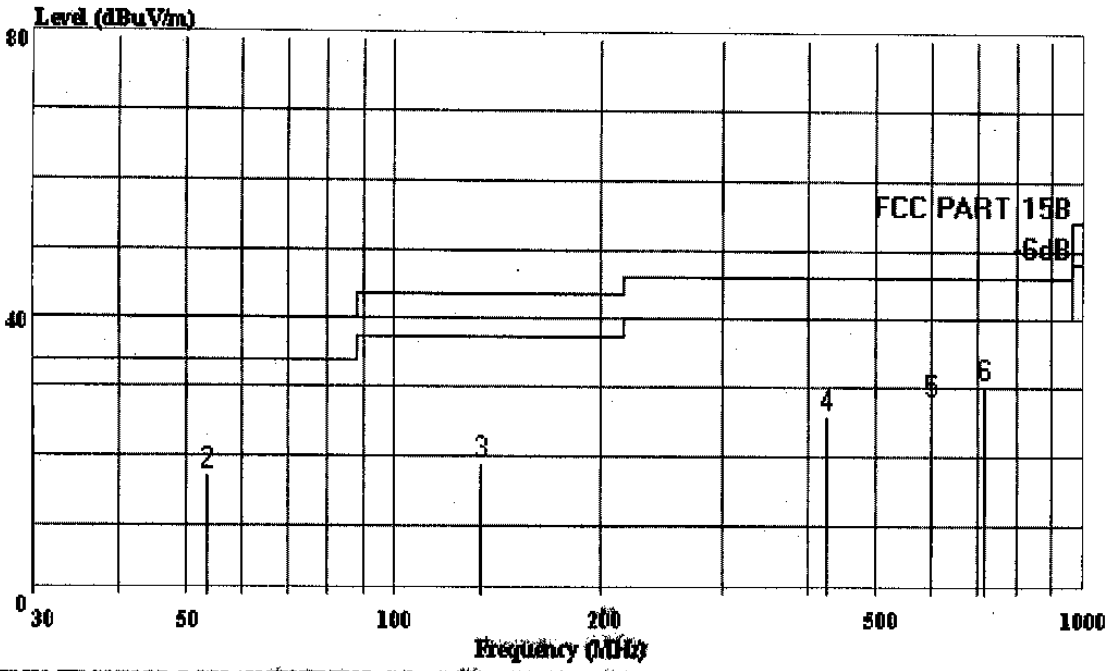
Data#: 6 File#: Sharper.EMI Date: 2004-09-12 Time: 12:13:05



AUDIX TECHNOLOGY (SHENZHEN) CO., LTD. (3# Chamber)

Trace: Ref Trace:

Condition: FCC PART 15B 3m 2598FACTOR VERTICAL
EUT : NYCFI-DUO
M/N : SI367
Power : Battery DC 3V
Engineer : Seco
Test Mode: On (Rx)
Memo : Temp:24'C Humi:56%
: Antpos:1.1m Tablepos:316'

Page: 1

	Freq	Level	Over Limit	Limit Line	Read Level	Probe Factor	Cable Loss
	MHz	dBuV/m	dB	dBuV/m	dBuV	dB	dB
1	30.000	22.92	-17.08	40.00	8.48	13.39	1.05
2	53.280	17.34	-22.66	40.00	9.61	6.32	1.41
3	133.790	19.13	-24.37	43.50	5.19	11.62	2.32
4	424.790	25.84	-20.16	46.00	4.79	16.27	4.78
5	599.390	28.22	-17.78	46.00	3.20	18.91	6.11
6	715.790	30.42	-15.58	46.00	2.64	21.16	6.62

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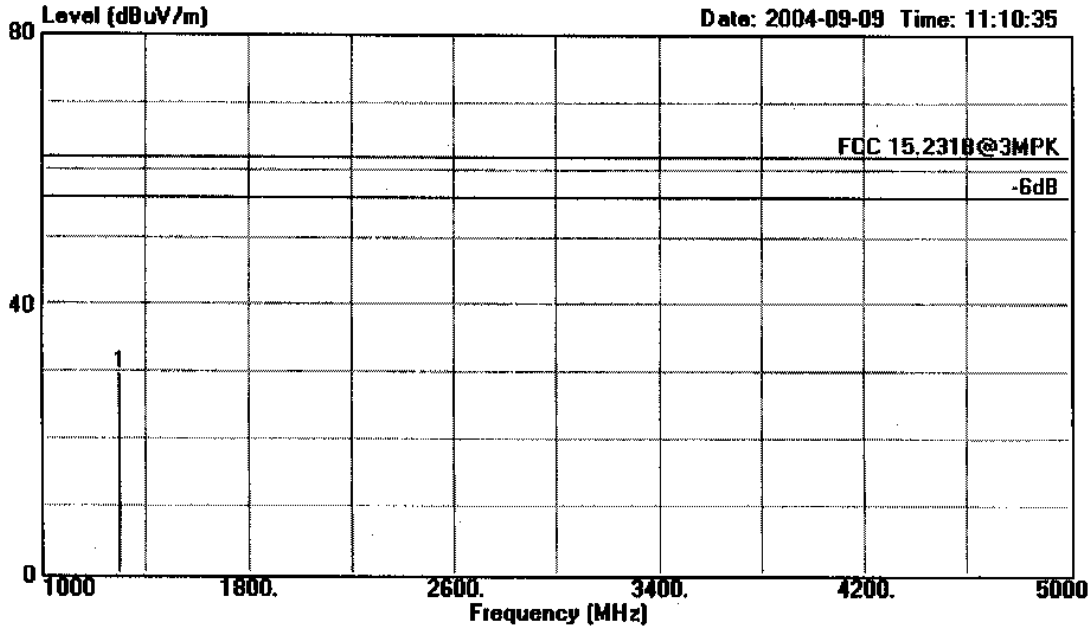
Data#: 5 File#: C:\EMI TEST DATA\S\Sharper.EMI



Site : 1# Chamber
Condition : FCC 15.231B@3MPK 3m 3115 FACTOR R HORIZONTAL
EUT : NYCFI-DUO
M/N : SI367
Power : Battery DC 3.0V
Test Engineer : Seco
Test Mode : On (Tx)
Memo : Temp:24'C Humi:56%

	Freq	Level	Over Limit	Limit Line	Read Level	Probe Factor	Cable Loss	Remark
	MHz	dBuV	dB	dBuV	dBuV	dB	dB	
1	1300.800	29.90	-32.00	61.90	1.84	25.00	3.06	Peak

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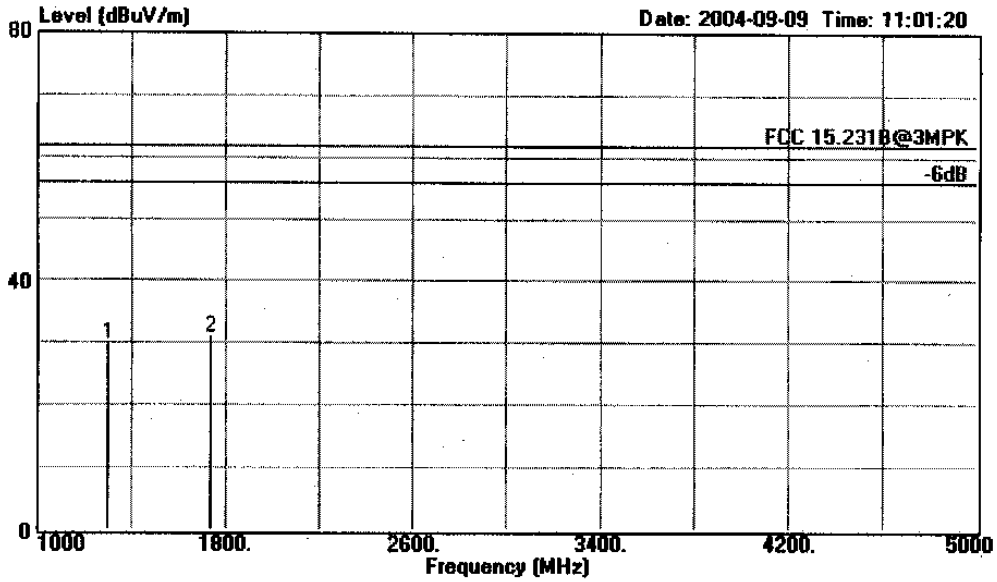
Data#: 3 File#: C:\EMI TEST DATA\S\Sharper.EMI



Site : 1# Chamber
Condition : FCC 15.231B@3MPK 3m 3115 FACTOR R VERTICAL
EUT : NYCFI-DUO
M/N : SI367
Power : Battery DC 3.0V
Test Engineer : Seco
Test Mode : On (Tx)
Memo : Temp:24'C Humi:56%

	Freq	Level	Over Limit	Limit Line	Read Level	Probe Factor	Cable Loss	Remark
	MHz	dBuV	dB	dBuV	dBuV	dB	dB	
1	1300.800	30.20	-31.70	61.90	2.14	25.00	3.06	Peak
2	1734.400	31.20	-30.70	61.90	2.52	26.69	1.99	Peak

4. BANDWIDTH TEST

4.1. Test Equipment

The following test equipments are used during the bandwidth test:

Item	Equipment	Manufacturer	Model No.	Serial No.	Last Cal.	Cal. Interval
1.	Spectrum	Agilent	E4407B	MY41440292	May 24, 04	1 Y
2.	Antenna	EMCO	3115	9607-4877	Jun 15, 04	1.5 Y

4.2. Test Standard

The test completeness FCC 15C (231).

4.3. Bandwidth Limit

The minimum 20dB bandwidth shall be at least 0.25% of the center frequency.

4.4. Test Procedure

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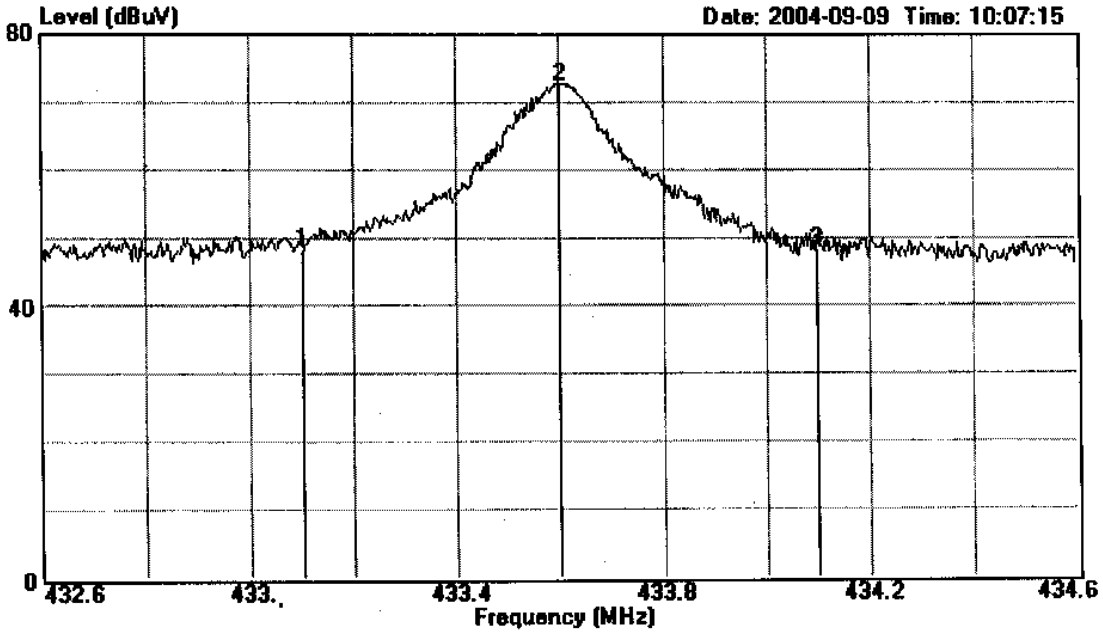
Data#: 1 File#: C:\EMI TEST DATA\S\Sharper.EMI



Site : 1# Chamber
Condition :
EUT : NYCFI-DUO
M/N : SI367
Power : Battery DC 3.0V
Test Engineer : Seco
Test Mode : On (Tx)
Memo : Temp:24'C Humi:56%

	Freq	Level	Over Limit	Limit Line	Read Level	Probe Factor	Cable Loss	Preamp Factor	Remark
	MHz	dBuV	dB	dBuV	dBuV	dB	dB	dB	
1	433.100	48.34	------	------	48.34	0.00	0.00	0.00	Peak
2	433.600	72.67	------	------	72.67	0.00	0.00	0.00	Peak
3	434.100	48.34	------	------	48.34	0.00	0.00	0.00	Peak

5. DEVIATION TO TEST SPECIFICATIONS

[NONE]

APPENDIX I

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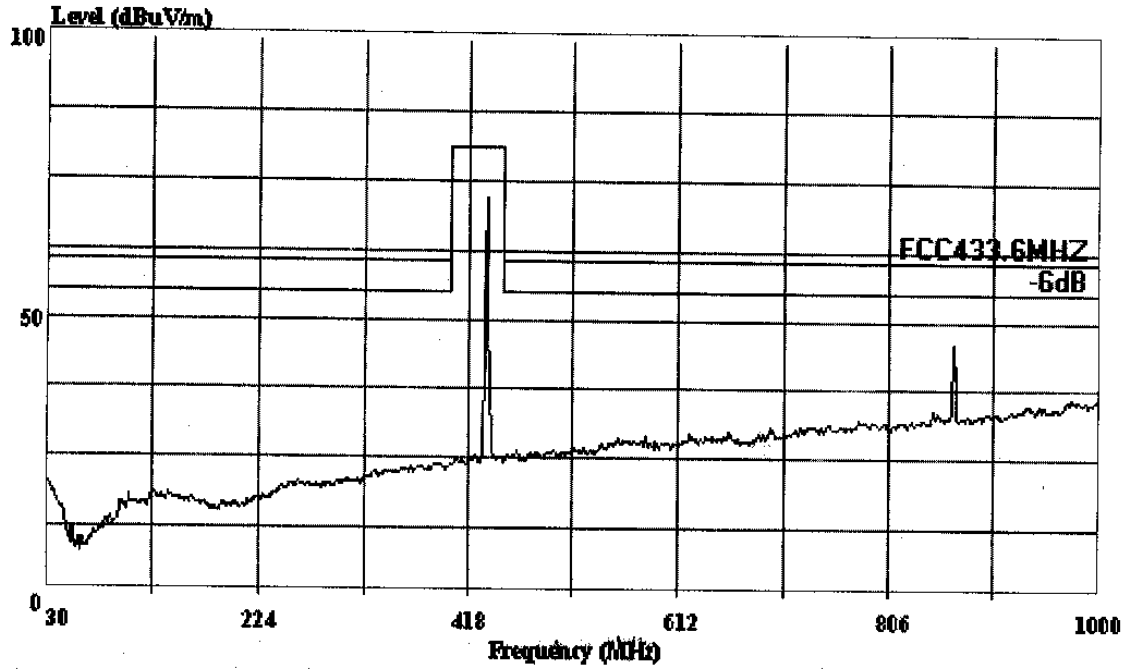
Data#: 1 File#: Sharper.EMI Date: 2004-09-12 Time: 11:30:08



Trace: Ref Trace:

Condition: FCC433.6MHZ 3m 2598FACTOR HORIZONTAL
EUT : NYCFT-DUO
M/N : SI367
Power : Battery DC 3V
Engineer : Seco
Test Mode: On (Tx)
Memo : Temp:24'C Humi:56%

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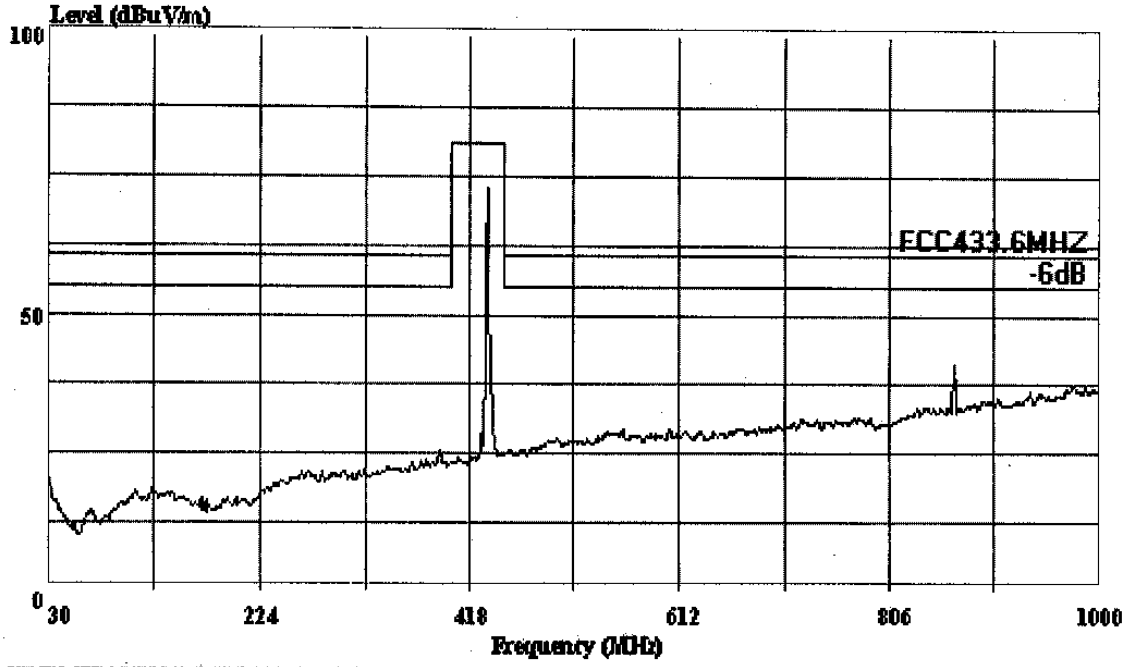
Data#: 3 File#: Sharper.EMI Date: 2004-09-12 Time: 11:45:18



Trace: Ref Trace:

Condition: FCC433.6MHZ 3m 2598FACTOR VERTICAL
EUT : NYCFI-DUO
M/N : SI367
Power : Battery DC 3V
Engineer : Seco
Test Mode: On (Tx)
Memo : Temp:24'C Humi:56%

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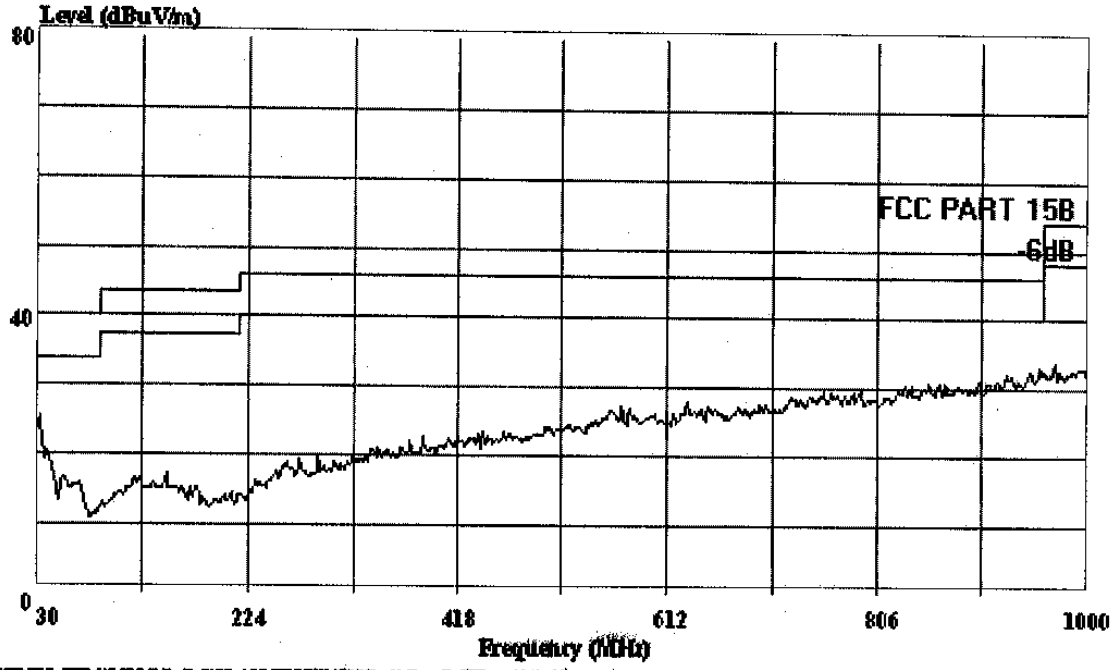
Data#: 7 File#: Sharper.EMI Date: 2004-09-12 Time: 12:15:12



Trace: Ref Trace:

Condition: FCC PART 15B 3m 2598FACTOR HORIZONTAL
EUT : NYCFI-DUO
M/N : SI367
Power : Battery DC 3V
Engineer : Seco
Test Mode: On (Rx)
Memo : Temp:24'C Humi:56%

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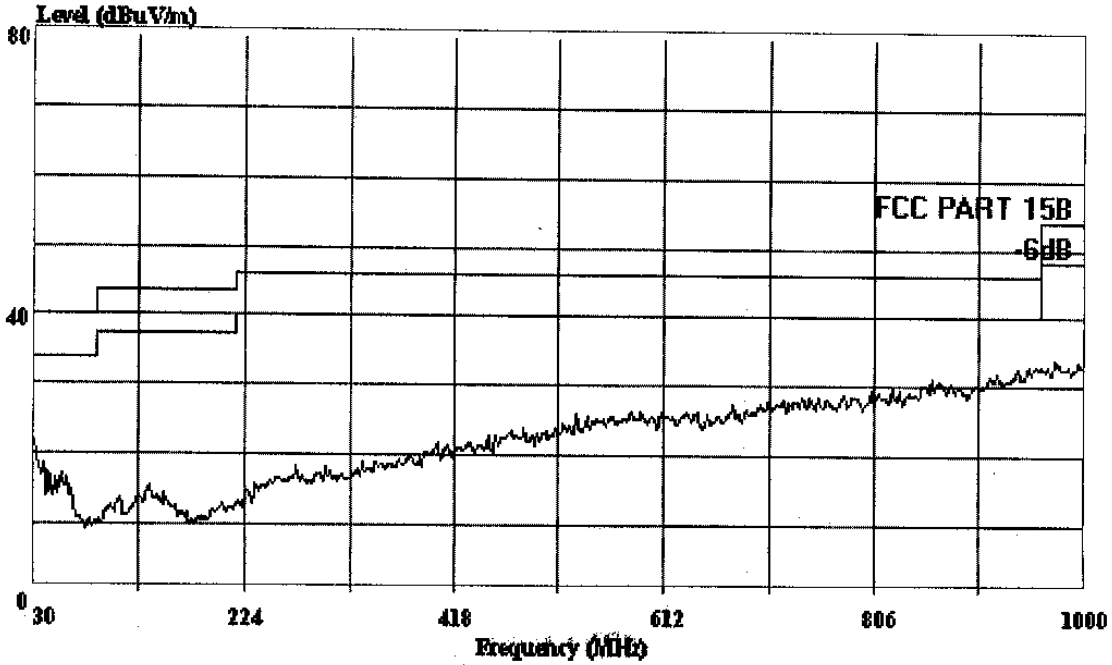
Fax: 0755-26632877

Data#: 5 File#: Sharper.EMI Date: 2004-09-12 Time: 12:11:06



Trace: Ref Trace:

Condition: FCC PART 15B 3m 2598FACTOR VERTICAL
EUT : NYCFI-DUO
M/N : SI367
Power : Battery DC 3V
Engineer : Seco
Test Mode: On (Rx)
Memo : Temp:24'C Humi:56%

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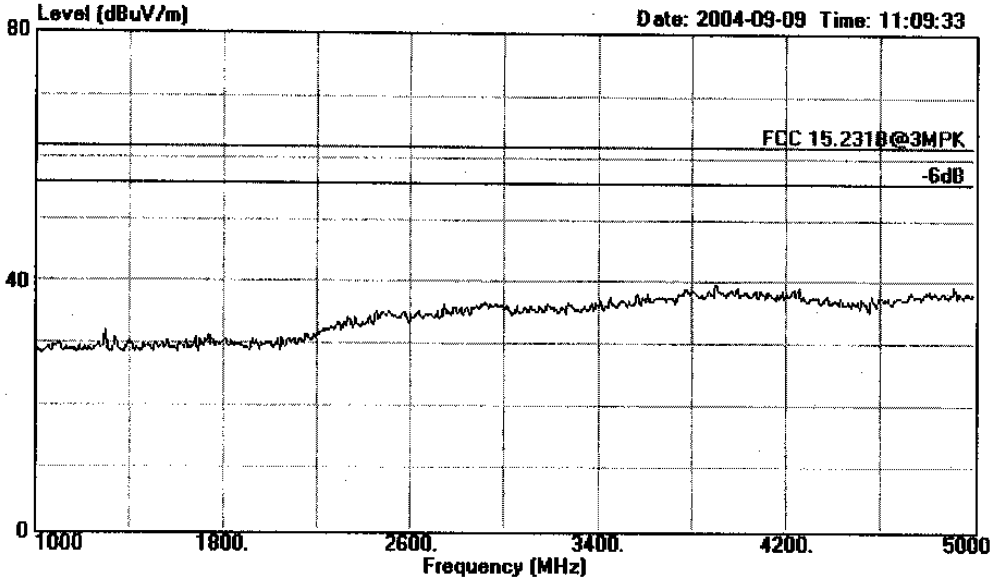
Tel:+86-755-26639496 Fax:+86-755-26632677

Data#: 4 File#: C:\EMI TEST DATA\S\Sharper.EMI



Site : 1# Chamber
Condition : FCC 15.231B@3MPK 3m 3115 FACTOR R HORIZONTAL
EUT : NYCFI-DUO
M/N : SI367
Power : Battery DC 3.0V
Test Engineer : Seco
Test Mode : On (Tx)
Memo : Temp:24'C Humi:56%

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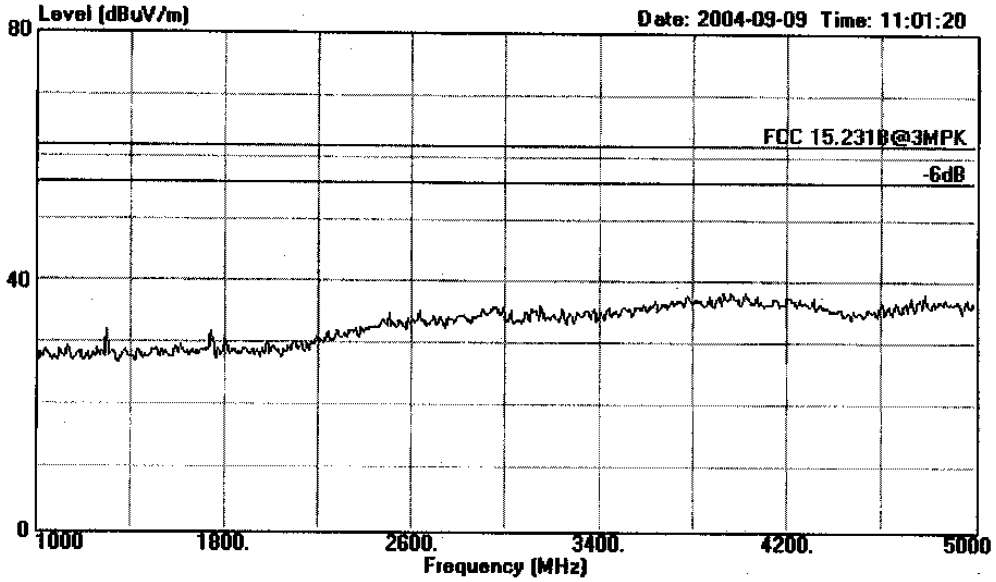
Data#: 2 File#: C:\EMI TEST DATA\S\Sharper.EMI



Site : 1# Chamber
Condition : FCC 15.231B@3MPK 3m 3115 FACTOR R VERTICAL
EUT : NYCFI-DUO
M/N : SI367
Power : Battery DC 3.0V
Test Engineer : Seco
Test Mode : On (Tx)
Memo : Temp:24'C Humi:56%

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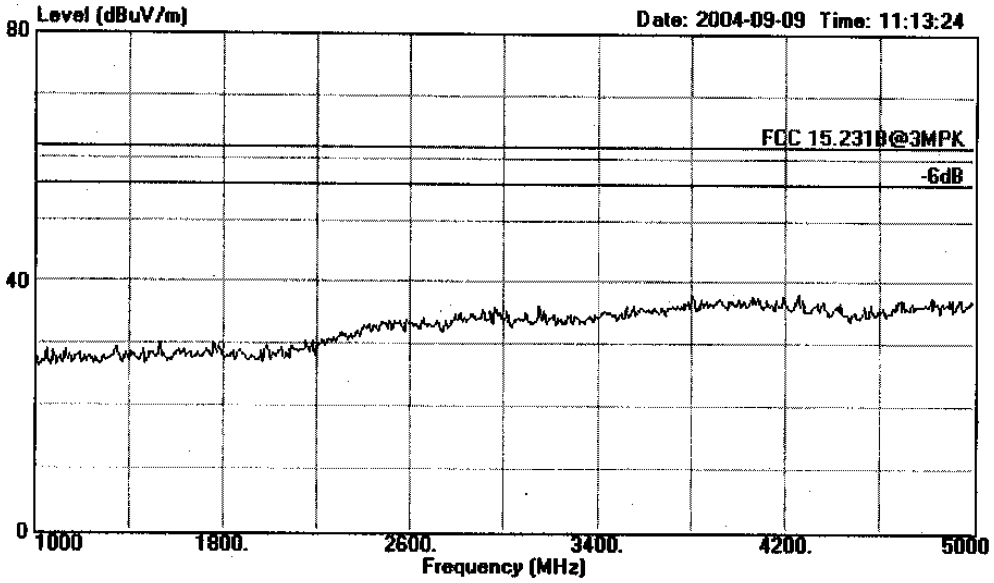
Data#: 6 File#: C:\EMI TEST DATA\S\Sharper.EMI



Site : 1# Chamber
Condition : FCC 15.231B@3MPK 3m 3115 FACTOR R HORIZONTAL
EUT : NYCFI-DUO
M/N : SI367
Power : Battery DC 3.0V
Test Engineer : Seco
Test Mode : On (Rx)
Memo : Temp:24'C Humi:56%

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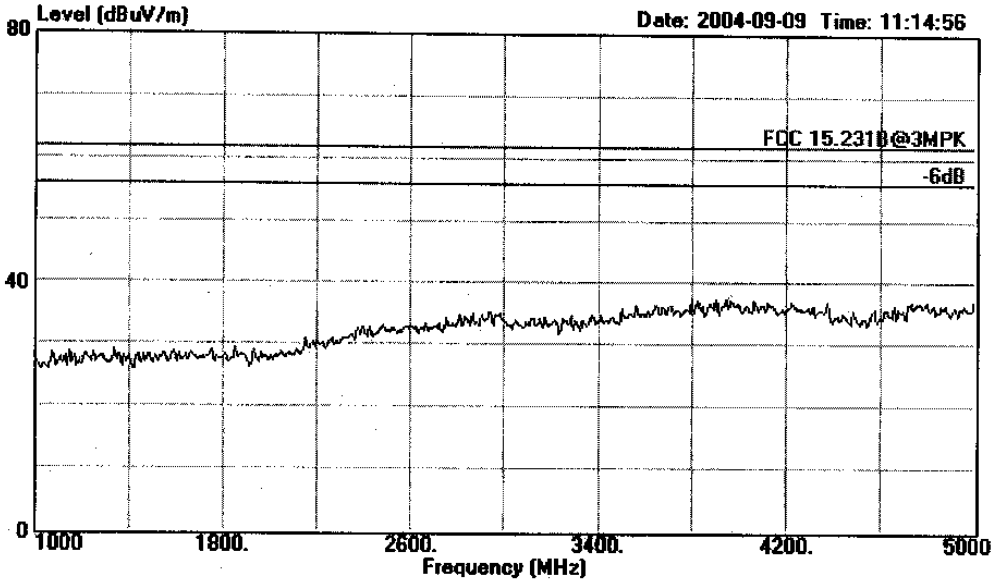
Data#: 7 File#: C:\EMI TEST DATA\S\Sharper.EMI



Site : 1# Chamber
Condition : FCC 15.231B@3MPK 3m 3115 FACTOR R VERTICAL
EUT : NYCFI-DUO
M/N : SI367
Power : Battery DC 3.0V
Test Engineer : Seco
Test Mode : On (Rx)
Memo : Temp:24'C Humi:56%